## FEATURES

- Wide frequency range: VHF, UHF and 900 MHz bands
- High sensitivity
- High dynamic range
- Electronically adjustable filters on chip
- Suitable for data rates up to 2400 bits/s
- Wide frequency offset and deviation range
- Fully POCSAG compatible FSK receiver
- Power on/off mode selectable by the chip enable input
- Low supply voltage; low power consumption
- 1-cell battery-low detection circuit
- High integration level
- Interfaces directly to the PCA5000A, PCF5001 and PCD5003 POCSAG decoders.


## APPLICATIONS

- Wide area paging
- On-site paging
- Telemetry
- RF security systems
- Low bit-rate wireless data links.


## GENERAL DESCRIPTION

The UAA2082 is a high-performance low-power radio receiver circuit primarily intended for VHF, UHF and 900 MHz pager receivers for wide area digital paging systems, employing direct FM non-return-to-zero (NRZ) frequency shift keying (FSK).

The receiver design is based on the direct conversion principle where the input signal is mixed directly down to the baseband by a local oscillator on the signal frequency. Two complete signal paths with signals of $90^{\circ}$ phase difference are required to demodulate the signal.
All channel selectivity is provided by the built-in IF filters. The circuit makes extensive use of on-chip capacitors to minimize the number of external components.

The battery monitoring circuit has an external sense input and a 1.1 V detection threshold for easy operation in a single-cell supply concept.
The UAA2082 was designed to operate together with the PCA5000A, PCF5001 or PCD5003 POCSAG decoders, which contain a digital input filter for optimum call success rate.

## ORDERING INFORMATION

| TYPE <br> NUMBER | PACKAGE |  |  |
| :---: | :---: | :--- | :---: |
|  | NAME | DESCRIPTION | VERSION |
| UAA2082H | LQFP32 | plastic low profile quad flat package; 32 leads; body $7 \times 7 \times 1.4 \mathrm{~mm}$ | SOT358-1 |
| UAA2082U | 28 pads | naked die; see Fig.8 |  |

Advanced pager receiver

## QUICK REFERENCE DATA

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{P}$ | supply voltage |  | 1.9 | 2.05 | 3.5 | V |
| $\mathrm{I}_{\mathrm{P}}$ | supply current |  | 2.3 | 2.7 | 3.2 | mA |
| $\mathrm{IP}_{(\text {(off) }}$ | stand-by current |  | - | - | 3 | $\mu \mathrm{A}$ |
| $\mathrm{P}_{\mathrm{i}(\text { ref) }}$ | RF input sensitivity | BER $\leq 3 / 100$; $\pm 4 \mathrm{kHz}$ deviation; data rate $1200 \mathrm{bits} / \mathrm{s} ; \mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C}$ $\begin{aligned} & \mathrm{f}_{(\text {(RF })}=173 \mathrm{MHz} \\ & \mathrm{f}_{\mathrm{i} \text { (RF) }}=470 \mathrm{MHz} \\ & \mathrm{f}_{\mathrm{i}(\mathrm{RF})}=930 \mathrm{MHz} \end{aligned}$ |  | $\begin{array}{\|l\|} \hline-126.5 \\ -124.5 \\ -120.0 \\ \hline \end{array}$ | $\begin{array}{\|l\|} \hline-123.5 \\ -121.5 \\ -114.0 \\ \hline \end{array}$ | dBm dBm dBm |
| $\mathrm{P}_{\mathrm{i}(\text { mix })}$ | mixer input sensitivity | BER $\leq 3 / 100 ;$ f $\mathrm{f}_{\mathrm{i}}$ (RF) $=470 \mathrm{MHz}$; $\pm 4 \mathrm{kHz}$ deviation; data rate $1200 \mathrm{bits} / \mathrm{s} ; \mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C}$ | - | -115.0 | -110.0 | dBm |
| $\mathrm{V}_{\text {th }}$ | detection threshold for battery LOW indicator | $\mathrm{T}_{\text {amb }}=25^{\circ} \mathrm{C}$ | 1.05 | 1.10 | 1.15 | V |
|  |  | $\mathrm{T}_{\text {amb }}=-10$ to $+70^{\circ} \mathrm{C}$ | 1.03 | 1.10 | 1.17 | V |
| $\mathrm{T}_{\text {amb }}$ | operating ambient temperature |  | -10 | - | +70 | ${ }^{\circ} \mathrm{C}$ |

## BLOCK DIAGRAMS (173 MHz)



Table 1 Tolerances of components shown in Figs 1 and 2 (notes 1 and 2)

| COMPONENT | TOLERANCE <br> (\%) | REMARK |
| :---: | :---: | :---: |
| Inductances |  |  |
| L1 | $\pm 5$ | $Q_{\text {min }}=100$ at 173 MHz |
| L2, L3, L6, L7 | $\pm 20$ | $\mathrm{Q}_{\text {min }}=50$ at $173 \mathrm{MHz} ; \mathrm{TC}=(+25$ to +125$) \times 10^{-6} / \mathrm{K}$ |
| L4, L5 | $\pm 10$ | $\mathrm{Q}_{\text {min }}=30$ at $173 \mathrm{MHz} ; \mathrm{TC}=(+25$ to +125$) \times 10^{-6} / \mathrm{K}$ |
| L8 | $\pm 20$ | $\mathrm{Q}_{\text {min }}=30$ at $173 \mathrm{MHz} ; \mathrm{TC}=(+25$ to +125$) \times 10^{-6} / \mathrm{K}$ |
| L9 | $\pm 10$ | $\mathrm{Q}_{\text {min }}=30$ at $57 \mathrm{MHz} ; \mathrm{TC}=(+25$ to +125$) \times 10^{-6} / \mathrm{K}$ |
| Resistors |  |  |
| R1 to R7 | $\pm 2$ | TC $=+50 \times 10^{-6} / \mathrm{K}$ |
| Capacitors |  |  |
| C1, C2, C7, C8, C9, C15 | $\pm 5$ | $\mathrm{TC}=(0 \pm 30) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 30 \times 10^{-4}$ at 1 MHz |
| C3, C6, C12 | - | TC $=(-750 \pm 300) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 50 \times 10^{-4}$ at 1 MHz |
| C4, C5, C14, C18, C19, C20 | $\pm 10$ | $\mathrm{TC}=(0 \pm 30) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 10 \times 10^{-4}$ at 1 MHz |
| C10, C11 | $\pm 5$ | $\mathrm{TC}=(0 \pm 30) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 21 \times 10^{-4}$ at 1 MHz |
| C13 | $\pm 20$ |  |
| C16 | - | TC $=(-1700 \pm 500) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 50 \times 10^{-4}$ at 1 MHz |
| C17 | $\pm 5$ | $\mathrm{TC}=(0 \pm 30) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 26 \times 10^{-4}$ at 1 MHz |

## Notes

1. Recommended crystal: $\mathrm{f}_{\mathrm{XTAL}}=57.647 \mathrm{MHz}$ (crystal with 8 pF load), 3rd overtone, pullability $>2.75 \times 10^{-6} / \mathrm{pF}$ (change in frequency between series resonance and resonance with 8 pF series capacitor at $25^{\circ} \mathrm{C}$ ), dynamic resistance $\mathrm{R} 1<40 \Omega, \Delta \mathrm{f}= \pm 5 \times 10^{-6}$ for $\mathrm{T}_{\mathrm{amb}}=-10$ to $+55^{\circ} \mathrm{C}$ with $25^{\circ} \mathrm{C}$ reference, calibration plus aging tolerance: $-5 \times 10^{-6}$ to $+15 \times 10^{-6}$.
2. This crystal recommendation is based on economic aspects and practical experience. Normally the spreads for R1, pullability and calibration do not show their worst case limits simultaneously in one crystal. In such a rare event, the tuning range will be reduced to an insufficient level.



Fig. 5 Mixer input sensitivity test circuit; $f_{i(R F)}=469.95 \mathrm{MHz}$.

Table 2 Tolerances of components shown in Figs 3, 4 and 5 (notes 1 and 2)

| COMPONENT | TOLERANCE <br> (\%) | REMARK |
| :---: | :---: | :---: |
| Inductances |  |  |
| L1, L10 | $\pm 5$ | $\mathrm{Q}_{\text {min }}=145$ at 470 MHz |
| L2, L3, L6, L7 | $\pm 20$ | $\mathrm{Q}_{\text {min }}=50$ at $470 \mathrm{MHz} ; \mathrm{TC}=(+25$ to +125$) \times 10^{-6} / \mathrm{K}$ |
| L4, L5 | $\pm 10$ | $\mathrm{Q}_{\text {min }}=40$ at 470 MHz ; TC $=(+25$ to +125$) \times 10^{-6} / \mathrm{K}$ |
| L8 | $\pm 10$ | $\mathrm{Q}_{\text {min }}=30$ at $156 \mathrm{MHz} ; \mathrm{TC}=(+25$ to +125$) \times 10^{-6} / \mathrm{K}$ |
| L9 | $\pm 10$ | $\mathrm{Q}_{\text {min }}=40$ at $78 \mathrm{MHz} ; \mathrm{TC}=(+25$ to +125$) \times 10^{-6} / \mathrm{K}$ |
| Resistors |  |  |
| R1 to R6 | $\pm 2$ | TC $=+50 \times 10^{-6} / \mathrm{K}$ |
| Capacitors |  |  |
| C1, C2, C7, C8, C9 | $\pm 5$ | TC $=(0 \pm 30) \times 10^{-6} / \mathrm{K}$; tan $\delta \leq 30 \times 10^{-4}$ at 1 MHz |
| C3, C6, C12, C23 | - | TC $=(-750 \pm 300) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 50 \times 10^{-4}$ at 1 MHz |
| C4, C5, C14, C18 to C22 | $\pm 10$ | TC $=(0 \pm 30) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 10 \times 10^{-4}$ at 1 MHz |
| C10, C11 | $\pm 5$ | TC $=(0 \pm 30) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 21 \times 10^{-4}$ at 1 MHz |
| C13 | $\pm 20$ |  |
| C16 | - | TC = (-1700 $\pm 500) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 50 \times 10^{-4}$ at 1 MHz |
| C17 | $\pm 5$ | $\mathrm{TC}=(0 \pm 30) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 26 \times 10^{-4}$ at 1 MHz |

## Notes

1. Recommended crystal: $\mathrm{f}_{\mathrm{XTAL}}=78.325 \mathrm{MHz}$ (crystal with 8 pF load), 3rd overtone, pullability $>2.75 \times 10^{-6} / \mathrm{pF}$ (change in frequency between series resonance and resonance with 8 pF capacitor at $25^{\circ} \mathrm{C}$ ), dynamic resistance $\mathrm{R} 1<30 \Omega, \Delta \mathrm{f}= \pm 5 \times 10^{-6}$ for $\mathrm{T}_{\mathrm{amb}}=-10$ to $+55^{\circ} \mathrm{C}$ with $25^{\circ} \mathrm{C}$ reference, calibration plus aging tolerance: $-5 \times 10^{-6}$ to $+15 \times 10^{-6}$.
2. This crystal recommendation is based on economic aspects and practical experience. Normally the spreads for R1, pullability and calibration do not show their worst case limits simultaneously in one crystal. In such a rare event, the tuning range will be reduced to an insufficient level.

## BLOCK AND TEST DIAGRAM (930 MHz)



Fig. 6 Test circuit; $\mathrm{f}_{\mathrm{i}(\mathrm{RF})}=930.50 \mathrm{MHz}$.

Table 3 Tolerances of components shown in Fig. 6 (note 1)

| COMPONENT | TOLERANCE (\%) | REMARK |
| :---: | :---: | :---: |
| Inductances |  |  |
| L1 | $\pm 10$ | $\mathrm{Q}_{\text {typ }}=150$ at 930 MHz |
| L2, L3, L6, L7 | - | microstrip inductor |
| L4, L5 | $\pm 5$ | $\mathrm{Q}_{\text {typ }}=100$ at 930 MHz |
| L8 | $\pm 10$ | $\mathrm{Q}_{\text {typ }}=65$ at 310 MHz |
| L10, L11 | $\pm 10$ | $\mathrm{Q}_{\text {typ }}=150$ at 930 MHz |
| Resistors |  |  |
| R1 to R4 | $\pm 2$ | TC $=(0 \pm 200) \times 10^{-6} / \mathrm{K}$ |
| Capacitors |  |  |
| C1, C2, C7, C8, C9, C15 | $\pm 5$ | TC $=(0 \pm 30) \times 10^{-6} / \mathrm{K}$; tan $\delta \leq 30 \times 10^{-4}$ at 1 MHz |
| C3, C6, C12 | - | TC $=(0 \pm 200) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 30 \times 10^{-4}$ at 1 MHz |
| C4, C5, C14, C19 | $\pm 10$ | $\mathrm{TC}=(0 \pm 30) \times 10^{-6} / \mathrm{K} ; \tan \delta \leq 10 \times 10^{-4}$ at 1 MHz |
| C13 | $\pm 20$ |  |

Note

1. The external oscillator signal $\mathrm{V}_{\mathrm{i}(\mathrm{OSC})}$ has a frequency of $\mathrm{f}_{\mathrm{OSC}}=310.1667 \mathrm{MHz}$.

## Advanced pager receiver

## PINNING (LQFP32)

| SYMBOL | PIN | DESCRIPTION |
| :--- | :---: | :--- |
| TS | 1 | test switch; connection to ground <br> for normal operation |
| BLI | 2 | battery LOW indicator output |
| DO | 3 | data output |
| RE | 4 | receiver enable input |
| TPI | 5 | IF test point; I channel |
| TPQ | 6 | IF test point; Q channel |
| VI1RF | 7 | pre-amplifier RF input 1 |
| VI2RF | 8 | pre-amplifier RF input 2 |
| n.c. | 9 | not connected |
| RRFA | 10 | external emitter resistor for <br> pre-amplifier |
| GND1 | 11 | ground 1 (0 V) |
| VO2RF | 12 | pre-amplifier RF output 2 |
| VO1RF | 13 | pre-amplifier RF output 1 |
| VP | 14 | supply voltage |
| VI2MI | 15 | I channel mixer input 2 |
| VI1MI | 16 | I channel mixer input 1 |
| n.c. | 17 | not connected |
| VI1MQ | 18 | Q channel mixer input 1 |
| VI2MQ | 19 | Q channel mixer input 2 |
| GND2 | 20 | ground 2 (0 V) |
| COM | 21 | gyrator filter resistor; common line |
| RGYR | 22 | gyrator filter resistor |
| n.c. | 23 | not connected |
| VO1MUL | 24 | frequency multiplier output 1 |
| VO2MUL | 25 | frequency multiplier output 2 |
| RMUL | 26 | external emitter resistor for <br> frequency multiplier |
| SENSE | 27 | battery LOW detector sense input |
| OSC | 28 | oscillator collector |
| n.c. | 29 | not connected |
| GND3 | 30 | ground 3 (0 V) |
| OSB | 31 | oscillator base; crystal input |
| OSE | 32 | oscillator emitter |
|  |  |  |



Fig. 7 Pin configuration; LQFP32.

## Advanced pager receiver

## CHIP DIMENSIONS AND BONDING PAD LOCATIONS

See Table 4 for bonding pad description and locations for $\mathrm{x} / \mathrm{y}$ co－ordinates．


Where：
O Pad number 1 （diameter $124 \mu \mathrm{~m}$ ）
$\square$ Pad $124 \mu \mathrm{~m} \times 124 \mu \mathrm{~m}$
『 Pad not used
［囲 Pad $100 \mu \mathrm{~m} \times 100 \mu \mathrm{~m}$
圈 Pad $100 \mu \mathrm{~m} \times 100 \mu \mathrm{~m}$ with reference point

Chip area： $18.15 \mathrm{~mm}^{2}$
Chip thickness： $380 \pm 20 \mu \mathrm{~m}$ ．
Drawing not to scale．
Fig． 8 Bonding pad locations．

## Advanced pager receiver

Table 4 Bonding pad centre locations (dimensions in $\mu \mathrm{m}$ )

| SYMBOL | PAD |  | DESCRIPTION | $\mathbf{y}$ |
| :--- | :---: | :--- | :--- | :--- |
| TPI | 1 | IF test point; I channel | -32 | 1296 |
| TPQ | 2 | IF test point; Q channel | -32 | 1000 |
| VI1RF | 3 | pre-amplifier RF input 1 | -32 | 360 |
| VI2RF | 4 | pre-amplifier RF input 2; note 1 | 0 | 0 |
| RRFA | 5 | external emitter resistor for pre-amplifier | 472 | 0 |
| GND1 | 6 | ground 1 (0 V) | 1160 | 0 |
| VO2RF | 7 | pre-amplifier RF output 2 | 1688 | 0 |
| VO1RF | 8 | pre-amplifier RF output 1 | 2232 | 0 |
| VP | 9 | supply voltage | 2760 | 0 |
| VI2MI | 10 | I channel mixer input 2 | 3608 | 0 |
| VI1MI | 11 | I channel mixer input 1 | 4216 | 0 |
| VI1MQ | 12 | Q channel mixer input 1 | 4216 | 360 |
| VI2MQ | 13 | Q channel mixer input 2 | 4216 | 960 |
| GND2 | 14 | ground 2 (0 V) | 4216 | 1360 |
| COM | 15 | gyrator filter resistor; common line | 4216 | 2024 |
| RGYR | 16 | gyrator filter resistor | 4216 | 2496 |
| VO1MUL | 17 | frequency multiplier output 1 | 4216 | 3136 |
| VO2MUL | 18 | frequency multiplier output 2 | 4176 | 3456 |
| RMUL | 19 | external emitter resistor for frequency multiplier | 3668 | 3458 |
| SENSE | 20 | battery LOW detector sense input | 2952 | 3456 |
| OSC | 21 | oscillator collector | 2312 | 3456 |
| GND3 | 22 | ground 3 (0 V) | 1832 | 3456 |
| OSB | 23 | oscillator base; crystal input | 1328 | 3456 |
| OSE | 24 | oscillator emitter | 432 | 3456 |
| TS | 25 | test switch; connection to ground for normal operation | -32 | 3456 |
| BLI | 26 | battery LOW indicator output | -32 | 3136 |
| DO | 27 | data output | -32 | 2512 |
| RE | 28 | receiver enable input | -32 | 2152 |
|  |  | lower left corner of chip (typical values) | -278 | -186 |

## Note

1. All $x / y$ co-ordinates are referenced to the centre of pad 4 (VI2RF); see Fig.8.


Fig. 9 Internal circuits drawn for LQFP32.


## FUNCTIONAL DESCRIPTION

The complete circuit consists of the following functional blocks as shown in Figs 1 to 6.

## Radio frequency amplifier

The RF amplifier is an emitter-coupled pair driving a balanced cascode stage, which drives an external balanced tuned circuit. Its bias current is set by an external $300 \Omega$ resistor R1 to typically $770 \mu \mathrm{~A}$. With this bias current the optimum source resistance is $1.3 \mathrm{k} \Omega$ at VHF and $1.0 \mathrm{k} \Omega$ at UHF. At 930 MHz a higher bias current is required to achieve optimum gain. A value of $120 \Omega$ is used for R1, which corresponds with a bias current of approximately 1.3 mA and an optimum source resistance of approximately $600 \Omega$.The capacitors C 1 and C2 transform a $50 \Omega$ source resistance to this optimum value. The output drives a tuned circuit with capacitive divider (C7, C8 and C9) to provide maximum power transfer to the phase-splitting network and the mixers.

## Mixers

The double balanced mixers consist of common base input stages and upper switching stages driven from the frequency multiplier. The $300 \Omega$ input impedance of each mixer acts together with external components (C10, C11; L4, L5 respectively) as phase shifter/power splitter to provide a differential phase shift of 90 degrees between the I channel and the Q channel. At 930 MHz all external phase shifter components are inductive (L10, L11; L4, L5).

## Oscillator

The oscillator is based on a transistor in common collector configuration. It is followed by a cascode stage driving a tuned circuit which provides the signal for the frequency multiplier. The oscillator transistor requires an external bias voltage $\mathrm{V}_{\text {bias(osc) }}$ ( 1.22 V typ.). The oscillator bias current (typically $250 \mu \mathrm{~A}$ ) is determined by the $1.5 \mathrm{k} \Omega$ external resistor R5. The oscillator frequency is controlled by an external 3rd overtone crystal in parallel resonance mode. External capacitors between base and emitter (C17) and from emitter to ground (C16) make the oscillator transistor appear as having a negative resistance for small signals; this causes the oscillator to start. Inductance L9 connected in parallel with capacitor C16 to the emitter of the oscillator transistor prevents oscillation at the fundamental frequency of the crystal.

The resonant circuit at output pin OSC selects the second harmonic of the oscillator frequency. In other applications a different multiplication factor may be chosen.
At 930 MHz an external oscillator circuit is required to provide sufficient local oscillator signal for the frequency multiplier.

## Frequency multiplier

The frequency multiplier is an emitter-coupled pair driving an external balanced tuned circuit. Its bias current is set by external resistor R4 to typically $190 \mu \mathrm{~A}(173 \mathrm{MHz}), 350 \mu \mathrm{~A}$ ( 470 MHz ) and $1 \mathrm{~mA}(930 \mathrm{MHz}$ ). The oscillator signal is internally AC coupled to one input of the emitter-coupled pair while the other input is internally grounded via a capacitor. The frequency multiplier output signal between pins VO1MUL and VO2MUL drives the upper switching stages of the mixers. The bias voltage on pins VO1MUL and VO2MUL is set by external resistor R3 to allow sufficient voltage swing at the mixer outputs. The value of R3 depends on the operating frequency: $1.5 \mathrm{k} \Omega$ $(173 \mathrm{MHz}), 820 \Omega(470 \mathrm{MHz})$ and $330 \Omega(930 \mathrm{MHz})$.

## Low noise amplifiers, active filters and gyrator filters

The low noise amplifiers ensure that the noise of the following stages does not affect the overall noise figure. The following active filters before the gyrator filters reduce the levels of large signals from adjacent channels. Internal AC couplings block DC offsets from the gyrator filter inputs.

The gyrator filters implement the transfer function of a 7th order elliptic filter. Their cut-off frequencies are determined by the $47 \mathrm{k} \Omega$ external resistor R2 between pins RGYR and COM. The gyrator filter output signals are available on IF test pins TPI and TPQ.

## Limiters

The gyrator filter output signals are amplified in the limiter amplifiers to obtain IF signals with removed amplitude information.

## Demodulator

The limiter amplifier output signals are fed to the demodulator. The demodulator output DO is going LOW or HIGH depending upon which of the input signals has a phase lead.

## Battery LOW indicator

The battery LOW indicator senses the supply voltage and sets its output HIGH when the voltage at input SENSE is less than $\mathrm{V}_{\text {th }}$ (typically 1.10 V ). Low battery warning is available at BLI.

## Band gap reference

The whole chip except the oscillator section can be powered-up and powered-down by enabling and disabling the band gap reference via the receiver enable pin RE.

## LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).
Ground pins GND1, GND2 and GND3 connected together.

| SYMBOL | PARAMETER | MIN. | MAX. | UNIT |
| :--- | :--- | :--- | :--- | :--- |
| $\mathrm{V}_{\mathrm{P}}$ | Supply voltage | -0.3 | +8.0 | V |
| $\mathrm{~T}_{\text {stg }}$ | storage temperature | -55 | +125 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{amb}}$ | operating ambient temperature | -10 | +70 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{V}_{\mathrm{es}}$ | electrostatic handling; note 1 |  |  |  |
|  | pins VI1RF and VI2RF | -1500 | +2000 | V |
|  | pin RRFA | -500 | +2000 | V |
|  | pins VO1RF and VO2RF | -2000 | +250 | V |
|  | pins VP and OSB | -500 | +500 | V |
|  | pins OSC and OSE | -2000 | +500 | V |
|  | other pins | -2000 | +2000 | V |

## Note

1. Equivalent to discharging a 100 pF capacitor via a $1.5 \mathrm{k} \Omega$ resistor.

## DC CHARACTERISTICS

$\mathrm{V}_{\mathrm{P}}=2.05 \mathrm{~V} ; \mathrm{T}_{\mathrm{amb}}=-10$ to $+70^{\circ} \mathrm{C}$ (typical values at $\mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C}$ ); measurements taken in test circuit Figs $1,2,3$ or 4 with crystal at pin OSB disconnected; unless otherwise specified.

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Supply |  |  |  |  |  |  |
| $\mathrm{V}_{P}$ | supply voltage |  | 1.9 | 2.05 | 3.5 | V |
| $\mathrm{I}_{P}$ | supply current | $\begin{aligned} & \mathrm{V}_{\text {RE }}=\mathrm{HIGH} ; \\ & \left.\mathrm{f}_{\mathrm{i}} \mathrm{RF}\right)=173 \text { and } 470 \mathrm{MHz} \\ & \hline \end{aligned}$ | 2.3 | 2.7 | 3.2 | mA |
|  |  | $\mathrm{V}_{\text {RE }}=\mathrm{HIGH} ; \mathrm{f}_{\mathrm{i}}(\mathrm{RF})=930 \mathrm{MHz}$ | 2.9 | 3.4 | 3.9 | mA |
| $\mathrm{I}_{\text {P(off) }}$ | stand-by current | $\mathrm{V}_{\text {RE }}=$ LOW | - | - | 3 | $\mu \mathrm{A}$ |
| $\mathrm{V}_{\text {bias(osc) }}$ | oscillator bias voltage |  | 1.20 | 1.22 | 1.24 | V |

## Receiver enable input (pin RE)

| $\mathrm{V}_{\mathrm{IH}}$ | HIGH level input voltage |  | 1.4 | - | $\mathrm{V}_{\mathrm{P}}$ | V |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- |
| $\mathrm{V}_{\mathrm{IL}}$ | LOW level input voltage |  | 0 | - | 0.3 | V |
| $\mathrm{I}_{\mathrm{IH}}$ | HIGH level input current | $\mathrm{V}_{\mathrm{IH}}=\mathrm{V}_{\mathrm{P}}=3.5 \mathrm{~V}$ | - | - | 20 | $\mu \mathrm{~A}$ |
| $\mathrm{~V}_{\mathrm{IL}}$ | LOW level input current | $\mathrm{V}_{\mathrm{IL}}=0 \mathrm{~V}$ | 0 | - | -1.0 | $\mu \mathrm{~A}$ |

## Battery LOW indicator output (pin BLI)

| $\mathrm{V}_{\text {OH }}$ | HIGH level output voltage | $\mathrm{V}_{\text {SENSE }}<\mathrm{V}_{\mathrm{th}} ; \mathrm{I}_{\mathrm{BLI}}=-10 \mu \mathrm{~A}$ | $\mathrm{~V}_{\mathrm{P}}-0.5$ | - | - | V |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- |
| $\mathrm{V}_{\mathrm{OL}}$ | LOW level output voltage | $\mathrm{V}_{\mathrm{SENSE}}>\mathrm{V}_{\mathrm{th}} ; \mathrm{I}_{\mathrm{BL}}=+10 \mu \mathrm{~A}$ | - | - | 0.5 | V |
| $\mathrm{~V}_{\text {th }}$ | voltage threshold for battery <br> LOW indicator | $\mathrm{V}_{\mathrm{P}}=2.05 \mathrm{~V} ; \mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C}$ | 1.05 | 1.10 | 1.15 | V |
|  | $\mathrm{V}_{\mathrm{P}}=2.05$ to $3.5 \mathrm{~V} ;$ <br> $\mathrm{T}_{\mathrm{amb}}=-10$ to $+70^{\circ} \mathrm{C}$ | 1.03 | 1.10 | 1.17 | V |  |

## Demodulator output (pin DO)

| $\mathrm{V}_{\mathrm{OH}}$ | HIGH level output voltage | $\mathrm{I}_{\mathrm{DO}}=-10 \mu \mathrm{~A}$ | $\mathrm{~V}_{\mathrm{P}}-0.5$ | - | - | V |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- |
| $\mathrm{V}_{\mathrm{OL}}$ | LOW level output voltage | $\mathrm{I}_{\mathrm{DO}}=+10 \mu \mathrm{~A}$ | - | - | 0.5 | V |

## AC CHARACTERISTICS ( 173 MHz )

$V_{P}=2.05 \mathrm{~V} ; \mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C}$; test circuit Figs 1 or $2 ; \mathrm{f}_{\mathrm{i}(\mathrm{RF})}=172.941 \mathrm{MHz}$ with $\pm 4.0 \mathrm{kHz}$ deviation; 1200 baud pseudo random bit sequence modulation ( $\mathrm{t}_{\mathrm{r}}=250 \pm 25 \mu \mathrm{~s}$ measured between $10 \%$ and $90 \%$ of voltage amplitude) and 20 kHz channel spacing; unless otherwise specified.

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Radio frequency input |  |  |  |  |  |  |
| $\mathrm{P}_{\mathrm{i}(\text { ref) }}$ | input sensitivity ( $\mathrm{P}_{\mathrm{i} \text { (ref) }}$ is the maximum available power at the RF input of the test board) | BER $\leq 3 / 100$; note 1 | - | -126.5 | -123.5 | dBm |
|  |  | $\mathrm{T}_{\text {amb }}=-10$ to $+70^{\circ} \mathrm{C}$; note 2 | - | - | -120.5 | dBm |
|  |  | $\mathrm{V}_{\mathrm{P}}=1.9 \mathrm{~V}$ | - | - | -117.5 | dBm |
| Mixers to demodulator |  |  |  |  |  |  |
| $\alpha_{\text {acs }}$ | adjacent channel selectivity | $\mathrm{T}_{\text {amb }}=25^{\circ} \mathrm{C}$ | 69 | 72 | - | dB |
|  |  | $\mathrm{T}_{\text {amb }}=-10$ to $+70^{\circ} \mathrm{C}$ | 67 | - | - | dB |
| $\alpha_{\text {ci }}$ | IF filter channel imbalance |  | - | - | 2 | dB |
| $\alpha_{c}$ | co-channel rejection |  | - | 4 | 7 | dB |
| $\alpha_{\text {sp }}$ | spurious immunity |  | 50 | 60 | - | dB |
| $\alpha_{\text {im }}$ | intermodulation immunity |  | 55 | 60 | - | dB |
| $\alpha_{b l}$ | blocking immunity | $\Delta \mathrm{f}> \pm 1 \mathrm{MHz}$; note 3 | 78 | 85 | - | dB |
| $\mathrm{f}_{\text {offset }}$ | frequency offset range (3 dB degradation in sensitivity) | deviation $\mathrm{f}= \pm 4.0 \mathrm{kHz}$ | $\pm 2.0$ | - | - | kHz |
|  |  | deviation $\mathrm{f}= \pm 4.5 \mathrm{kHz}$ | $\pm 2.5$ | - | - | kHz |
| $\Delta f_{\text {dev }}$ | deviation range (3 dB degradation in sensitivity) |  | 2.5 | - | 7.0 | kHz |
| $\mathrm{t}_{\text {on }}$ | receiver turn-on time | data valid after setting RE input HIGH; note 4 | - | - | 5 | ms |

## Notes

1. The bit error rate BER is measured using the test facility shown in Fig.12. Note that the BER test facility contains a digital input filter equivalent to the one used in the PCA5000A, PCF5001 and PCD5003 POCSAG decoders.
2. Capacitor C 16 requires re-adjustment to compensate temperature drift.
3. $\Delta f$ is the frequency offset between the required signal and the interfering signal.
4. Turn-on time is defined as the time from pin RE going HIGH to the reception of valid data on output pin DO. Turn-on time is measured using an external oscillator (turn-on time using the internal oscillator is dependent upon the oscillator circuitry).

## AC CHARACTERISTICS ( 470 MHz )

$V_{P}=2.05 \mathrm{~V} ; \mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C}$; test circuit Figs 3 or $4 ; \mathrm{f}_{\mathrm{i}(\mathrm{RF})}=469.950 \mathrm{MHz}$ with $\pm 4.0 \mathrm{kHz}$ deviation; 1200 baud pseudo random bit sequence modulation ( $\mathrm{t}_{\mathrm{r}}=250 \pm 25 \mu$ s measured between $10 \%$ and $90 \%$ of voltage amplitude) and 20 kHz channel spacing; unless otherwise specified.

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Radio frequency input |  |  |  |  |  |  |
| $\mathrm{P}_{\mathrm{i}(\text { ref) }}$ | input sensitivity ( $\mathrm{P}_{\mathrm{i} \text { (ref) }}$ is the maximum available power at the RF input of the test board) | BER $\leq 3 / 100$; note 1 | - | -124.5 | -121.5 | dBm |
|  |  | $\mathrm{T}_{\text {amb }}=-10$ to $+70^{\circ} \mathrm{C}$; note 2 | - | - | -118.5 | dBm |
|  |  | $\mathrm{V}_{\mathrm{P}}=1.9 \mathrm{~V}$ | - | - | -115.5 | dBm |
| Mixer input |  |  |  |  |  |  |
| $\mathrm{P}_{\mathrm{i}(\text { mix })}$ | input sensitivity | BER $\leq 3 / 100$; note 3 | - | -115.0 | -110.0 | dBm |
| Mixers to demodulator |  |  |  |  |  |  |
| $\alpha_{\text {acs }}$ | adjacent channel selectivity | $\mathrm{T}_{\text {amb }}=25^{\circ} \mathrm{C}$ | 67 | 70 | - | dB |
|  |  | $\mathrm{T}_{\text {amb }}=-10$ to $+70^{\circ} \mathrm{C}$ | 65 | - | - | dB |
| $\alpha_{\mathrm{ci}}$ | IF filter channel imbalance |  | - | - | 2 | dB |
| $\alpha_{c}$ | co-channel rejection |  | - | 4 | 7 | dB |
| $\alpha_{\text {sp }}$ | spurious immunity |  | 50 | 60 | - | dB |
| $\alpha_{\text {im }}$ | intermodulation immunity |  | 55 | 60 | - | dB |
| $\alpha_{\text {b }}$ | blocking immunity | $\Delta \mathrm{f}> \pm 1 \mathrm{MHz}$; note 4 | 75 | 82 | - | dB |
| $\mathrm{f}_{\text {offset }}$ | frequency offset range (3 dB degradation in sensitivity) | deviation $\mathrm{f}= \pm 4.0 \mathrm{kHz}$ | $\pm 2.0$ | - | - | kHz |
|  |  | deviation $\mathrm{f}= \pm 4.5 \mathrm{kHz}$ | $\pm 2.5$ | - | - | kHz |
| $\Delta \mathrm{f}_{\text {dev }}$ | deviation range (3 dB degradation in sensitivity) |  | 2.5 | - | 7.0 | kHz |
| $\mathrm{t}_{\text {on }}$ | receiver turn-on time | data valid after setting RE input HIGH; note 5 | - | - | 5 | ms |

## Notes

1. The bit error rate BER is measured using the test facility shown in Fig.12. Note that the BER test facility contains a digital input filter equivalent to the one used in the PCA5000A, PCF5001 and PCD5003 POCSAG decoders.
2. Capacitor C 16 requires re-adjustment to compensate temperature drift.
3. Test circuit Fig.5. $\mathrm{P}_{\mathrm{i}(\text { mix })}$ is the maximum available power at the input of the test board. The bit error rate BER is measured using the test facility shown in Fig.12.
4. $\Delta f$ is the frequency offset between the required signal and the interfering signal.
5. Turn-on time is defined as the time from pin RE going HIGH to the reception of valid data on output pin DO. Turn-on time is measured using an external oscillator (turn-on time using the internal oscillator is dependent upon the oscillator circuitry).

## AC CHARACTERISTICS ( 930 MHz )

$V_{P}=2.05 \mathrm{~V} ; \mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C}$; test circuit Fig. 6 ; note $1 ; \mathrm{f}_{\mathrm{i}}(\mathrm{RF})=930.500 \mathrm{MHz}$ with $\pm 4.0 \mathrm{kHz}$ deviation; 1200 baud pseudo random bit sequence modulation ( $\mathrm{t}_{\mathrm{r}}=250 \pm 25 \mu \mathrm{~s}$ measured between $10 \%$ and $90 \%$ of voltage amplitude) and 20 kHz channel spacing; unless otherwise specified.

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Radio frequency input |  |  |  |  |  |  |
| $\mathrm{P}_{\mathrm{i} \text { (ref) }}$ | input sensitivity ( $\mathrm{P}_{\mathrm{i}(\text { ref })}$ is the maximum available power at the RF input of the test board) | BER $\leq 3 / 100$; note 2 | - | -120.0 | -114.0 | dBm |
|  |  | $\mathrm{V}_{\mathrm{P}}=1.9 \mathrm{~V}$ | - | - | -108.0 | dBm |
| Mixers to demodulator |  |  |  |  |  |  |
| $\alpha_{\text {acs }}$ | adjacent channel selectivity | $\mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C}$ | 60 | 69 | - | dB |
| $\alpha_{c}$ | co-channel rejection |  | - | 5 | 10 | dB |
| $\alpha_{\text {sp }}$ | spurious immunity |  | 40 | 60 | - | dB |
| $\alpha_{\text {im }}$ | intermodulation immunity |  | 53 | 60 | - | dB |
| $\alpha_{b l}$ | blocking immunity | $\Delta \mathrm{f}> \pm 1 \mathrm{MHz}$; note 3 | 65 | 74 | - | dB |
| $\mathrm{f}_{\text {offset }}$ | frequency offset range (3 dB degradation in sensitivity) | deviation $\mathrm{f}= \pm 4.0 \mathrm{kHz}$ | $\pm 2.0$ | - | - | kHz |
|  |  | deviation $\mathrm{f}= \pm 4.5 \mathrm{kHz}$ | $\pm 2.5$ | - | - | kHz |
| $\Delta \mathrm{f}_{\text {dev }}$ | deviation range (3 dB degradation in sensitivity) |  | 2.5 | - | 7.0 | kHz |
| $\mathrm{t}_{\mathrm{on}}$ | receiver turn-on time | data valid after setting RE input HIGH; note 4 | - | - | 5 | ms |

## Notes

1. The external oscillator signal $\mathrm{V}_{\mathrm{i}(\mathrm{OSC})}$ has a frequency of $\mathrm{f}_{\mathrm{OSC}}=310.1667 \mathrm{MHz}$ and a level of -15 dBm .
2. The bit error rate BER is measured using the test facility shown in Fig.12. Note that the BER test facility contains a digital input filter equivalent to the one used in the PCA5000A, PCF5001 and PCD5003 POCSAG decoders.
3. $\Delta f$ is the frequency offset between the required signal and the interfering signal.
4. Turn-on time is defined as the time from pin RE going HIGH to the reception of valid data on output pin DO. Turn-on time is measured using an external oscillator (turn-on time using the internal oscillator is dependent upon the oscillator circuitry).

## TEST INFORMATION

## Tuning procedure for AC tests

1. Turn on the signal generator: $\mathrm{f}_{\text {gen }}=\mathrm{f}_{\mathrm{i}(\mathrm{RF})}+4 \mathrm{kHz}$, no modulation, $\mathrm{V}_{\mathrm{i}(\mathrm{RF})}=1 \mathrm{mV}$ (RMS).
2. Measure the IF with a counter connected to test pin TPI. Tune C16 to set the crystal oscillator to achieve $f_{\mathrm{IF}}=4 \mathrm{kHz}$ Change the generator frequency to $f_{g e n}=f_{i(R F)}-4 \mathrm{kHz}$ and check that $f_{I F}$ is also 4 kHz . For a received input frequency $f_{i(R F)}=172.941 \mathrm{MHz}$ the crystal frequency is $f_{\text {XTAL }}=57.647 \mathrm{MHz}$, while for $f_{i(R F)}=469.950 \mathrm{MHz}$ the crystal frequency is $f_{\text {XTAL }}=78.325 \mathrm{MHz}$. For a received input frequency $\mathrm{f}_{\mathrm{i}(\mathrm{RF})}=930.500 \mathrm{MHz}$ an external oscillator signal must be used with $\mathrm{f}_{\mathrm{i}(\mathrm{OSC})}=310.1667 \mathrm{MHz}$ and a level of -15 dBm (for definition of crystal frequency, see Table 1).
3. Set the signal generator to nominal frequency ( $\mathrm{f}_{\mathrm{i} \text { (RF) })}$ ) and turn on the modulation deviation $\pm 4.0 \mathrm{kHz}, 600 \mathrm{~Hz}$ square wave modulation, $\mathrm{V}_{\mathrm{i}(\mathrm{RF})}=1 \mathrm{mV}(\mathrm{RMS})$. Note that the RF signal should be reduced in the following tests, as the receiver is tuned, to ensure $\mathrm{V}_{0(\mathbb{F})}=10$ to $50 \mathrm{mV}(\mathrm{p}-\mathrm{p})$ on test pins TPI or TPQ.
4. Tune C15 (oscillator output circuit) and C12 (frequency multiplier output) to obtain a peak audio voltage on pin TPI.
5. Tune C3 and C6 (RF input and mixer input) to obtain a peak audio voltage on pin TPI. When testing the mixer input sensitivity tune C23 instead of C3 and C6 (test circuit Fig.5).
6. Check that the output signal on pin TPQ is within 3 dB in amplitude and at $90^{\circ}\left( \pm 20^{\circ}\right)$ relative phase of the signal on pin TPI.
7. Check that data signal appears on output pin DO and proceed with the AC test.

## AC test conditions

Table 5 Definitions for AC test conditions (see Table 6)

| SIGNAL |  |
| :--- | :--- |
| DESCRIPTION |  |
| Modulated test signal 1 |  |
| Frequency | $172.941,469.950$ or 930.500 MHz |
| Deviation | $\pm 4.0 \mathrm{kHz}$ |
| Modulation | 1200 baud pseudo random bit sequence |
| Rise time | $250 \pm 25 \mu \mathrm{~s}$ (between $10 \%$ and $90 \%$ of final value) |
| Modulated test signal 2 |  |
| Deviation | $\pm 2.4 \mathrm{kHz}$ |
| Modulation | 400 Hz sine wave |
| Other definitions |  |
| $\mathrm{f}_{1}$ | frequency of signal generator 1 |
| $\mathrm{f}_{2}$ | frequency of signal generator 2 |
| $\mathrm{f}_{3}$ | frequency of signal generator 3 |
| $\Delta \mathrm{f}_{\mathrm{cs}}$ | channel spacing (20 kHz) |
| $\mathrm{P}_{1}$ | maximum available power from signal generator 1 at the test board input |
| $\mathrm{P}_{2}$ | maximum available power from signal generator 2 at the test board input |
| $\mathrm{P}_{3}$ | maximum available power from signal generator 3 at the test board input |
| $\mathrm{P}_{\mathrm{i} \text { (ref) }}$ | maximum available power at the test board input to give a Bit Error Rate (BER) $\leq 3 / 100$ <br> test signal 1, in the absence of interfering signals and under the conditions as specified in Chapters <br> "AC characteristics (173 MHz)", "AC characteristics (470 MHz)" and "AC characteristics (930 MHz)" |

## Advanced pager receiver

Table 6 AC test conditions; notes 1 and 2

| SYMBOL | PARAMETER | CONDITIONS | TEST SIGNALS |
| :---: | :---: | :---: | :---: |
| $\alpha_{a}$ | adjacent channel selectivity; Fig.11(b) | $\begin{aligned} & \mathrm{f}_{2}=\mathrm{f}_{1} \pm \Delta \mathrm{f}_{\mathrm{CS}} \\ & \text { generator 1: modulated test signal } 1 \\ & \text { generator 2: modulated test signal } 2 \\ & \hline \end{aligned}$ | $\begin{aligned} & \mathrm{P}_{1}=\mathrm{P}_{\mathrm{i}(\mathrm{ref})}+3 \mathrm{~dB} \\ & \mathrm{P}_{2}=\mathrm{P}_{1}+\alpha_{\mathrm{a}(\mathrm{~min})} \end{aligned}$ |
| $\alpha_{c}$ | co-channel rejection; Fig.11(b) | $\begin{aligned} & \mathrm{f}_{2}=\mathrm{f}_{1} \pm \mathrm{up} \text { to } 3 \mathrm{kHz} \\ & \text { generator 1: modulated test signal } 1 \\ & \text { generator 2: modulated test signal } 2 \end{aligned}$ | $\begin{aligned} & P_{1}=P_{i(\text { ref })}+3 \mathrm{~dB} \\ & \mathrm{P}_{2}=\mathrm{P}_{1}-\alpha_{\mathrm{c}(\text { max })} \end{aligned}$ |
| $\alpha_{\text {sp }}$ | spurious immunity; Fig.11(b) | $\begin{aligned} & \hline \mathrm{f}_{2}=100 \mathrm{kHz} \text { to } 2 \mathrm{GHz} \\ & \text { generator 1: modulated test signal } 1 \\ & \text { generator 2: modulated test signal } 2 \\ & \hline \end{aligned}$ | $\begin{aligned} & P_{1}=P_{i(\text { ref })}+3 d B \\ & P_{2}=P_{1}+\alpha_{\text {sp }(\text { min })} \\ & \hline \end{aligned}$ |
| $\alpha_{\text {im }}$ | intermodulation immunity; Fig.11(c) | $f_{2}=f_{1} \pm \Delta f_{c s} ; f_{3}=f_{1} \pm 2 \Delta f_{c s}$ <br> generator 1: modulated test signal 1 <br> generator 2: unmodulated <br> generator 3: modulated test signal 2 | $\begin{aligned} & \mathrm{P}_{1}=\mathrm{P}_{\mathrm{i}(\text { ref })}+3 \mathrm{~dB} \\ & \mathrm{P}_{2}=\mathrm{P}_{1}+\alpha_{\mathrm{im}(\text { min })} \\ & \mathrm{P}_{3}=\mathrm{P}_{2} \\ & \hline \end{aligned}$ |
| $\alpha_{b}$ | blocking immunity; Fig.11(b) | $\begin{aligned} & \hline \mathrm{f}_{2}=\mathrm{f}_{1} \pm 1 \mathrm{MHz} \\ & \text { generator 1: modulated test signal } 1 \\ & \text { generator 2: modulated test signal } 2 \\ & \hline \end{aligned}$ | $\begin{aligned} & P_{1}=P_{i(\text { ref })}+3 d B \\ & P_{2}=P_{1}+\alpha_{b l(\text { min })} \end{aligned}$ |
| $\mathrm{f}_{\text {offset }}$ | frequency offset range; Fig.11(a) | deviation $= \pm 4.0 \mathrm{kHz}, \mathrm{f}_{1}=\mathrm{f}_{\mathrm{i} \text { (RF) }} \pm 2 \mathrm{kHz}\left(\mathrm{f}_{\text {offset(min) }}\right)$ <br> generator 1: modulated test signal 1 | $\mathrm{P}_{1}=\mathrm{P}_{\mathrm{i} \text { (ref) })}+3 \mathrm{~dB}$ |
| $\Delta \mathrm{f}_{\text {dev }}$ | deviation range; Fig.11(a) | deviation $= \pm 2.5$ to $\pm 7 \mathrm{kHz} ;\left(\Delta \mathrm{f}_{\operatorname{dev}(\min )}\right.$ to $\left.\Delta \mathrm{f}_{\operatorname{dev}(\max )}\right)$ <br> generator 1: modulated test signal 1 | $\mathrm{P}_{1}=\mathrm{P}_{\mathrm{i} \text { (ref) })}+3 \mathrm{~dB}$ |
| ton | receiver turn-on time; Fig.11(a) | note 3 generator 1: modulated test signal 1 | $\mathrm{P}_{1}=\mathrm{P}_{\mathrm{i}(\text { (ref) }}+10 \mathrm{~dB}$ |

## Notes

1. The tests are executed without load on pins TPI and TPQ.
2. All minimum and maximum values correspond to a bit error rate $(B E R) \leq 3 / 100$ in the wanted signal $\left(P_{1}\right)$.
3. The BER measurement is started $5 \mathrm{~ms}\left(\mathrm{t}_{\mathrm{on}(\text { max })}\right)$ after $\mathrm{V}_{\text {RE }}$ goes HIGH ; BER is then measured for 100 bits ( $B E R \leq 3 / 100$ ).
(a)

(b)

(c)

(a) One generator.
(b) Two generators.
(c) Three generators.
(1) See Fig. 12.

Fig. 11 Test configurations.


Fig. 12 BER test facility.

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## PRINTED-CIRCUIT BOARDS



Fig. 13 PCB top view for LQFP32; test circuit Figs 1 and 3.

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MBD561

Fig. 14 PCB bottom view for LQFP32; test circuit Figs 1 and 3.

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MLC234
$\mathrm{V}_{\mathrm{EE}}=\mathrm{GND} ; \mathrm{V}_{\mathrm{C}}=\mathrm{V}_{\mathrm{P}}$.
Fig. 15 PCB top view with components for LQFP32; test circuit Fig.3.

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Fig. 16 PCB bottom view with components for LQFP32; test circuit Fig.3.

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Fig. 17 PCB top view with components for LQFP32; test circuit Fig.5.

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Fig. 18 PCB bottom view with components for LQFP32; test circuit Fig.5.


Fig. 19 PCB top view with components for LQFP32; test circuit Fig.6.

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Fig. 20 PCB bottom view with components for LQFP32; test circuit Fig. 6.

